

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Horst Groeninger

Serial No.: Not yet assigned
(Priority Application No. 10 2004 007 696.0)
(International Application No. PCT/DE2005/000216)

Filed: Herewith
(Priority Date: 16 February 2004)
(International Filing Date: 9 February 2005)

Docket No.: I431.172.101/FIN574PCT/US

Title: **TEST APPARATUS FOR TESTING A SEMICONDUCTOR DEVICE, AND
METHOD FOR TESTING THE SEMICONDUCTOR DEVICE (as amended)**

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

This Preliminary Amendment amends the Utility Patent Application filed herewith and should be used to calculate filing fees due. Prior to examination of the above-identified patent application, please amend as follows:

Preliminary Amendment

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IN THE TITLE

Please replace the title with the following amended title:

TEST APPARATUS FOR TESTING A SEMICONDUCTOR DEVICE HAVING
CONTACT PADS ON ITS TOP AND ITS BOTTOM, AND METHOD FOR TESTING
THE SEMICONDUCTOR DEVICE